

WEBINAR

Reciprocal space mapping

X-ray diffraction



Date	05 June 2014
Time	10:00 AM EDT (4:00 PM CET)
Duration	45 minutes
Presenter	Lars Grieger, Application Specialist XRD PANalytical B.V., the Netherlands.

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This webinar focuses on data collection strategies and interpretation of reciprocal space maps from epitaxial layers. A walk through from data collection to data analysis is demonstrated in detailed steps for traditional high-resolution 0D optics and recent fast data collection strategies. The state-of-the-art 2D detectors allowing faster data collection expands the use of this technique from academic research or R&D to rapid quality control applications. Examples will be explained and quantified with our current analysis software Epitaxy 4.3a. Time for questions is reserved.

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